

# N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ (m $\Omega$ )(Typ.)	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ.)		
40	1.4 at V <sub>GS</sub> = 10 V	120	40 nC		
40	2.1 at V <sub>GS</sub> = 4.5 V	100	40110		

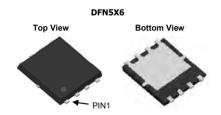
### **FEATURES**

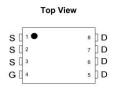
- DT-Trench Power MOSFET
- 100 %  $R_{\rm g}$  and UIS Tested

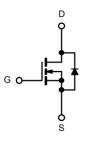


### **APPLICATIONS**

- Notebook PC Core
- VRM/POL







N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	40	V	
Gate-Source Voltage	V <sub>GS</sub>	± 20		
	T <sub>C</sub> = 25 °C		120 <sup>a, e</sup>	
Continuous Drain Current (T <sub>.I</sub> = 175 °C)	T <sub>C</sub> = 70 °C	_ [	100 <sup>e</sup>	
Continuous Drain Current (1j = 173 C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	38 <sup>b, c</sup>	A
	T <sub>A</sub> = 70 °C		26.9 <sup>b, c</sup>	
Pulsed Drain Current		I <sub>DM</sub>	420	
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	40	
Single Pulse Avalanche Energy	L = 0.111111	E <sub>AS</sub>	540	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	Is	120 <sup>a, e</sup>	_ A
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	'S	5.28 <sup>b, c</sup>	
	T <sub>C</sub> = 25 °C		140 <sup>a</sup>	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	98	w
	T <sub>A</sub> = 25 °C	' b	4.10 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		2.82 <sup>b, c</sup>	
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	15	18	°C/W	
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.45	0.7		

### Notes:

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
  d. Maximum under steady state conditions is 90 °C/W.
  e. Calculated based on maximum junction temperature.



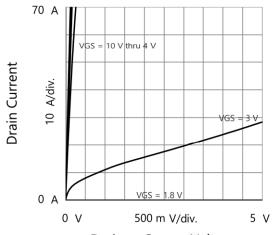
Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		35		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 5.5			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.2	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = 40 V, $V_{GS}$ = 0 V	1		1	T	
Zero Gate voltage Drain Current		$V_{DS} = 32 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		1.4	1.9		
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		2.1	2.9	mΩ	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A}$		78		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			2960		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 20 V, $V_{GS}$ = 0 V, f = 1 MHz		898			
Reverse Transfer Capacitance	C <sub>rss</sub>			63			
Total Gate Charge	$Q_g$			40		nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		5.8			
Gate-Drain Charge	Q <sub>gd</sub>			22			
Gate Resistance	R <sub>g</sub>	f = 1 MHz		14		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			16			
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 0.555 $\Omega$		10		ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20A$ , $V_{GEN} = 10 \text{ V}$ , $R_g = 1 \Omega$		56			
Fall Time	t <sub>f</sub>			10			
Turn-On Delay Time	t <sub>d(on)</sub>			12			
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 0.625 $\Omega$		150			
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		55			
Fall Time	t <sub>f</sub>			12			
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			120	A	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				420		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			35		ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 20 A di/dt = 100 A/vo T = 25 °C		90.2		nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		ns	
Reverse Recovery Rise Time	t <sub>b</sub>			25			

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

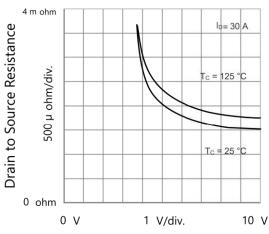
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



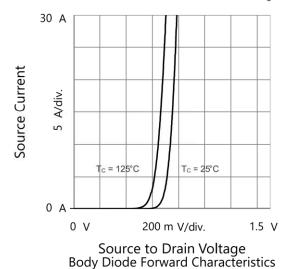
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Drain to Source Voltage Output Characteristics



Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage



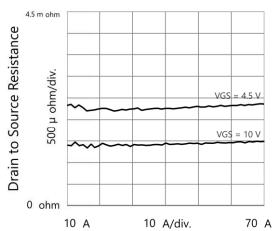
Drain Current

O A

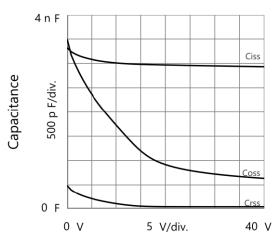
O V

300 m V/div. 3 V

Gate to Source Voltage Transfer Characteristics



Drain Current
Drain to Source Resistance vs. Drain Current

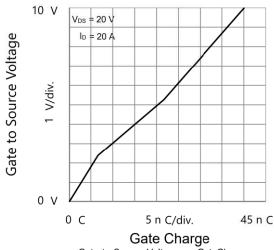


Drain to Source Voltage Capacitances

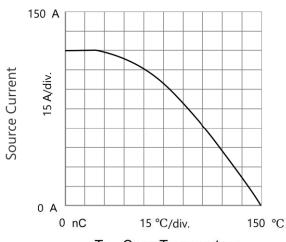




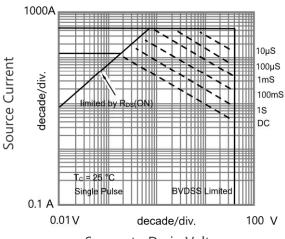
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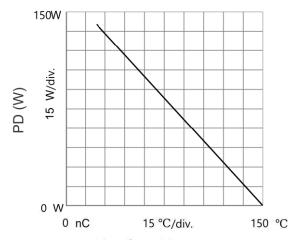
Gate to Source Voltage vs. GateCharge



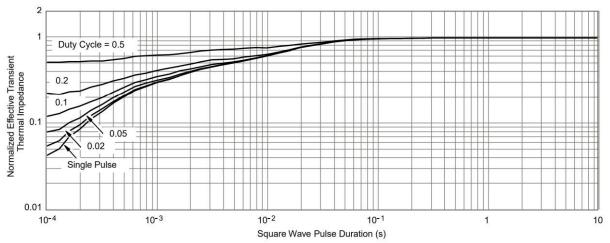
 $T_{C} \textbf{ - Case Temperature}_{\text{Current Derating}}$ 



Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



T<sub>C</sub> - Case Temperature Power Derating



Normalized Thermal Transient Impedance, Junction-to-Case





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